

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20131220003 Conversion to Cu bond wire Change Notification / Sample Request

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

PCN# 20131220003 Attachment: 1

Products Affected:

According to our records, there are the affected device(s) that you have purchased within the past twenty-four (24) months. Technical details of this Product Change follow on the next page(s).

PCN Number:		20131220003							PCN Date: 12/27		12/27/2013		
Title: Conversion to		o Cı	Cu bond wire										
Customer Contact:			PCI	N M	<u>anager</u>	Phone: +1(214)480		+1(214)480-6	6037 Dept: Q		Qua	uality Services	
Proposed 1 st Ship Da			ite:		03/27/2014		Es	timated Sam	ated Sample Availability:			12/27/2013	
Change Type:													
Assembly Site			\boxtimes	Assembly Process			\boxtimes	Assembly Materials					
Design				Electrical Specification				Mechanical Specification					
Test Site				Packing/Shipping/Labeling				Test Process					
☐ Wafer Bump Site					Wafer Bump Material				Wafer Bump Process				
☐ Wafer Fab Site					Wafer Fab Materials				Wafer Fab Process				
					Part number change				•				
PCN Details													

Description of Change:

Texas Instruments is pleased to announce the qualification of Cu as a bond wire option for the selected devices shown below. All listed devices will remain in current assembly facility and there will be no other BOM changes.

Reason for Change:

Continuity of supply.

- 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties
- 2) Maximize flexibility within our Assembly/Test production sites.
- 3) Cu is easier to obtain and stock

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

None affecting physical device marking. The 'REV' number on the labels will change for the CC112x/CC1175 and the CC2530FxxCRHA products.



Note that the following register changes will apply to the following products:

CC112x/CC1175:

Register 0x90 PARTVERSION. The new Reset value is 0x23.

CC2530F12CRHA and CC2530F25CRHA:

Register 0x6249 CHVER. The chip revision number will change.

Product Affected:							
CC1120RHBR	CC1125ARHBR	CC1175RHBT	CC1201RHBT				
CC1120RHBT	CC1125RHBR	CC1200RHBR	CC2530F12CRHA				
CC1121RHBR	CC1125RHBT	CC1200RHBT	CC2530F25CRHA				
CC1121RHBT	CC1175RHBR	CC1201RHBR					

Reference Qualification Data							
This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.							
Qual Vehicle: CC2533F96RHA (MSL 3-260C)							
Package Construction Details							
Assembly Site:	Clark AT Mold Compound:			4208625			
# Pins-Designator, Family:	40-RHA, VQFN Mount Compound:			4207123			
Lead Finish	NiPdAu	C	0.8mil Cu				
Qualification: Plan Test Results							
Poliability Tost	Conditions		Sample Size/Fail				
Reliability Test	Conditions	Lot#1	Lot#2	Lot#3			
** High Temp Operating Life	125C (168, 500, 100	39/0	39/0	38/0			
High Temp. Storage Bake	150C (168, 300, 600	77/0	77/0	77/0			
**Biased Temp. Humidity	85C/85%RH (168, 6	26/0	26/0	25/0			
**Unbiased HAST	110C/85%RH/17.7 p	77/0	77/0	77/0			
**T/C -65C/150C	-65C/+150C (500 C)	26/0	26/0	25/0			
**T/C -55C/125C	-55C/+125C (200, 7	77/0	77/0	77/0			
ESD CDM	+/- 100V, 250V, 500	3/0	3/0	3/0			
ESD HBM	+/- 500V, 1000V	3/0	3/0	3/0			
Latch-up	(per JESD78)	6/0	3/0	3/0			
Notes **- Preconditioning sequence: Level 3-260C.							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com